National Accreditation Board for
Testing and Calibration Laboratories

CERTIFICATE OF ACCREDITATION

EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH

has been assessed and accredited in accordance with the standard

ISO/IEC 17025:2017

"General Requirements for the Competence of Testing & Calibration Laboratories"

for its facilities at

SECTOR 7, RAIN TREE MARG, NAVI MUMBAI, THANE, MAHARASHTRA, INDIA

in the field of

TESTING

Certificate Number: TC-6969

Issue Date: 23/12/2020 **Valid Until:** 22/12/2022

This certificate remains valid for the Scope of Accreditation as specified in the annexure subject to continued satisfactory compliance to the above standard & the relevant requirements of NABL.
(To see the scope of accreditation of this laboratory, you may also visit NABL website www.nabl-india.org)

Name of Legal Identity : SOCIETY FOR APPLIED MICROWAVE ELECTRONICS ENGINEERING AND RESEARCH

Signed for and on behalf of NABL

N. Venkateswaran
Chief Executive Officer

SCOPE OF ACCREDITATION

Laboratory Name :	EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR 7, RAIN TREE MARG, NAVI MUMBAI, THANE, MAHARASHTRA, INDIA		
Accreditation Standard	ISO/IEC 17025:2017		
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S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
		Permanent Facility		
1	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 61000-6-1
2	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic equipment system/Subsystem	Conducted Emission	CE 102-MIL 461 E &F
3	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic equipment system/Subsystem	Conducted Emission	CE 101-MIL 461 E & F
4	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Bulk Cable Injection	CS 114-MIL 461 E & F
5	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Bulk cable Injection Impulse Excitation	CS 115-MIL 461 E & F
6	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Damped Sinusoidal Transients, Cable and Power Lead	CS 116 MIL 461 E & F
7	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Power Leads	CS101-MIL 461 E & F
8	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Structure Current	CS 109-MIL 461 E & F
9	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	CISPR 24
10	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 55024
11	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61000-6-1
12	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61000-6-2
13	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 61000-6-1
14	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 55011
15	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 55014-1
16	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 55015

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S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
17	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 61000-6-3
18	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	IEC 61000-6-3
19	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	IEC 61326-1
20	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	DC Voltage dips, Short Interruption & Voltage Variations Immunity Test	BS EN 61000-4-29
21	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 61000-4-2
22	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 61000-6-2
23	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 61326-1
24	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 55014-2
25	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 55024
26	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 55024
27	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	CISPR 14-2
28	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	CISPR 24
29	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	CISPR 35
30	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 60601-1-2
31	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 61000-6-1
32	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 61000-4-5
33	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 61000-6-2
34	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 55024

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S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
35	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 55014-2
36	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 60601-1-2
37	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 61000-4-8
38	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 61000-6-1
39	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 61000-6-2
40	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	CISPR 24
41	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	CISPR 35
42	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 60601-1-2
43	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 61000-6-1
44	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 61326-1
45	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	CISPR 32
46	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 55011
47	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 55014-1
48	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 55022
49	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 60601-1-2
50	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 61000-6-3
51	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 61000-6-4
52	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	CISPR 14-1
53	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	CISPR 22

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S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
54	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	IEC 60601-1-2
55	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	IEC 61000-6-3
56	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	IEC 61000-6-4
57	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	IEC 61326-1
58	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 61000-6-2
59	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	CISPR 24
60	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 60601-1-2
61	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 55014-2
62	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 55024
63	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 60601-1-2
64	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 61000-4-3
65	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 61000-6-1
66	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	CISPR 14-2
67	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	CISPR 35
68	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 61000-6-2
69	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 61326-1
70	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 55014-2
71	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 61000-4-11

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72	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	CISPR 14-2
73	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61326-1
74	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 60601-1-2
75	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	CISPR 35
76	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Voltage Fluctuation & Flicker Test	BS EN 60601-1-2
77	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Voltage Fluctuation & Flicker Test	BS EN 61000-3-3
78	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Voltage Fluctuation & Flicker Test	BS EN 61000-6-3
79	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Voltage Fluctuation & Flicker Test	IEC 60601-1-2
80	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Voltage Fluctuation & Flicker Test	IEC 61000-6-3
81	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 55022
82	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 60601-1-2
83	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 61000-6-4
84	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	CISPR 11
85	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	CISPR 14-1
86	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	CISPR 22
87	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	FCC Part 15B& 18
88	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	IEC 60601-1-2

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89	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	IEC 61000-6-4
90	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 55014-2
91	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 55024 + A1
92	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 60601-1-2
93	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 61000-4-6
94	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 61000-6-1
95	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 61000-6-2
96	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	CISPR 14-2
97	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	CISPR 24
98	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	CISPR 35
99	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	IEC 60601-1-2
100	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	IEC 61000-4-6
101	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	IEC 61000-6-1
102	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	IEC 61000-6-2
103	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Damped Oscillatory Wave Immunity Test	IEC 61000-4-12
104	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Damped Oscillatory wave Immunity Tests	BSEN 61000-4-18
105	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Damped Oscillatory wave Immunity Tests	IEC 61000-4-18
106	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	DC Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61000-4-29

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107	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 55014-2
108	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 55024
109	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 60601-1-2
110	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 61000-4-4
111	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 61000-6-1
112	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 61000-6-2
113	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	CISPR 24
114	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	CISPR 35
115	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 60601-1-2
116	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 61000-4-4
117	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 61000-6-1
118	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 61000-6-2
119	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 61326-1
120	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 60601-1-2
121	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 61000-6-1
122	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 61000-6-2
123	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 61000-4-2
124	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 55014-2
125	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 55024

SCOPE OF ACCREDITATION

Laboratory Name : EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR 7, RAIN TREE MARG, NAVI MUMBAI, THANE, MAHARASHTRA, INDIA

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126	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 60601-1-2
127	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 61000-6-1
128	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 61000-6-2
129	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	CISPR 24
130	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	CISPR 24
131	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	CISPR 35
132	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	CISPR14-2
133	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	IEC 60601-1-2
134	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	IEC 61000-6-1
135	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	IEC 61000-6-2
136	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	IEC 61326-1
137	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy/Telecom Surge Immunity Test	IEC 61000-4-5
138	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 61000-4-8
139	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	FCC Part 15B & 18
140	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Testing	CISPR 11
141	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 61000-4-3
142	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Ring Wave Immunity Test	BS EN 61000-4-12
143	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Ring Wave Immunity Test	IEC 61000-4-12

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144	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61000-4-11
145	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 61000-6-2
146	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 60601-1-2
147	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Voltage Fluctuation & Flicker Test	IEC 61000-3-3
148	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Conducted Emission	CISPR 15
149	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Conducted Emission	CISPR 32
150	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	BS EN 60601-1-2
151	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	BS EN 61000-3-2
152	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	BS EN 61000-6-3
153	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	IEC 60601-1-2
154	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	IEC 61000-6-3
155	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	IEC 61000-3-2
156	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronics products	Conducted RF Susceptibility Test	IEC 61326-1